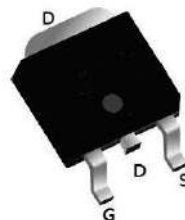


## N-Channel High Density Trench MOSFET

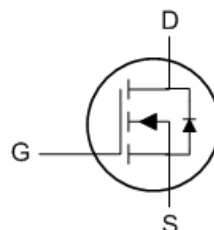
### Features:

- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology



### PRODUCT SUMMARY

V <sub>DSS</sub>	R <sub>DS(on)</sub> (m-ohm) Max	I <sub>D</sub>
100V	100 @ V <sub>GS</sub> = 10V	14.6 A
	110 @ V <sub>GS</sub> = 4.5V	



### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous <sup>1</sup>	I <sub>D</sub>	T <sub>c</sub> =25°C	14.6
		T <sub>c</sub> =100°C	10
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	25	A
Single Pulse Avalanche Energy <sup>3</sup>	EAS	0.8	mJ
Avalanche Current	I <sub>AS</sub>	4	A
Maximum Power Dissipation	P <sub>D</sub>	30.0	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	- 55 to 150	°C

### THERMAL CHARACTERISTICS

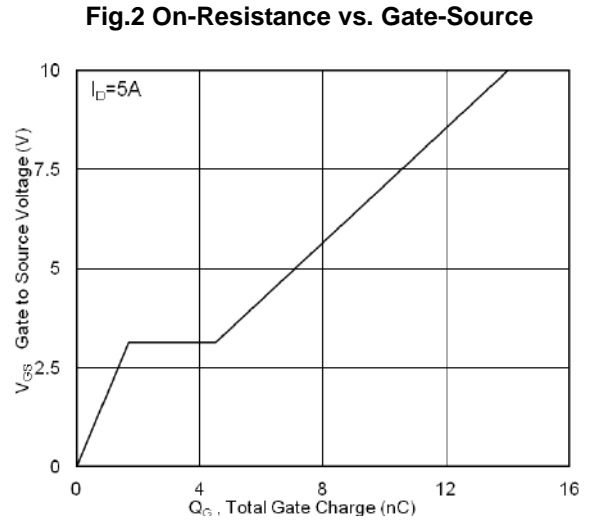
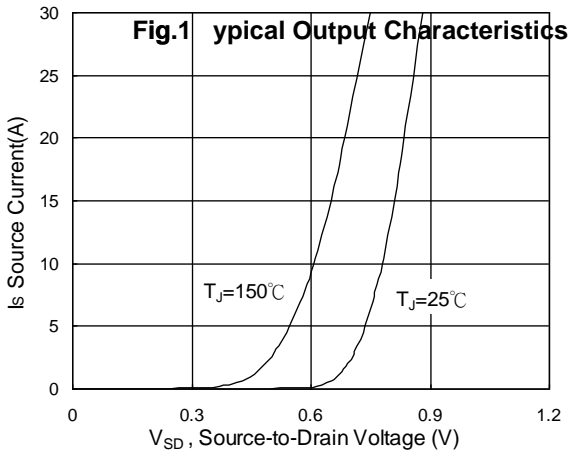
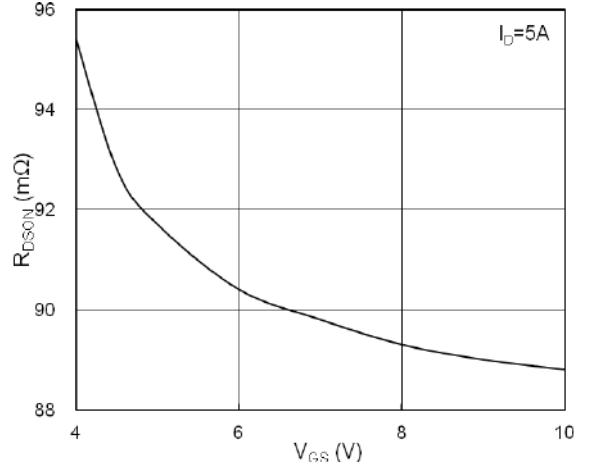
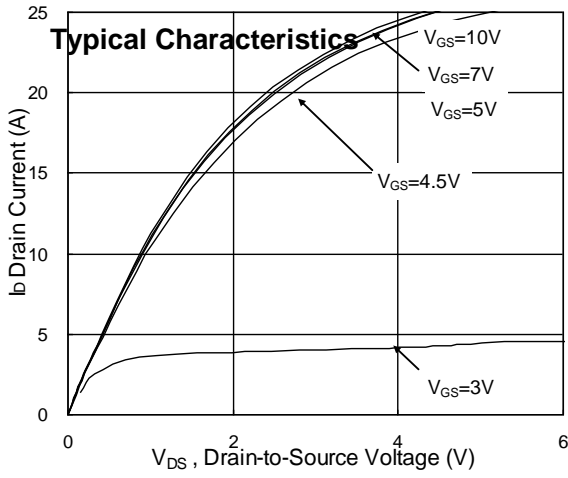
Thermal Resistance, Junction-to-Ambient <sup>1</sup>	R <sub>thJA</sub>	50	°C/W
Thermal Resistance, Junction-to-Case <sup>1</sup>	R <sub>thJC</sub>	3	°C/W

**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

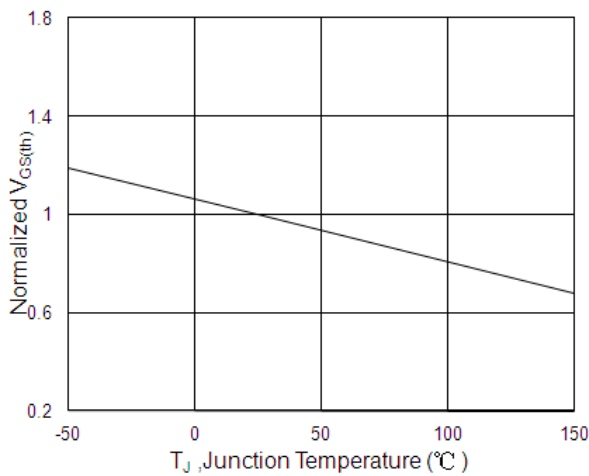
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80V, V_{GS} = 0V, T_j = 25^\circ C$			10	uA
		$V_{DS} = 80V, V_{GS} = 0V, T_j = 55^\circ C$			100	
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	1.2		2.9	V
Drain-Source On-State Resistance <sup>2</sup>	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 3A$			110	mΩ
		$V_{GS} = 10V, I_D = 5A$			100	mΩ
Gate Resistance	$R_g$	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		3		Ω
Forward Transconductance	$g_{fs}$	$V_{DS} = 5V, I_D = 5A$		14.0		S
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Continuous Current <sup>1,5</sup>	$I_S$	$V_G=V_D=0V, \text{Force Current}$			14.6	A
Pulsed Source Current <sup>2,5</sup>	$I_{SM}$				25	A
Diode Forward Voltage <sup>2</sup>	$V_{SD}$	$V_{GS} = 0V, I_S = 1A$			1.2	V
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	$C_{iSS}$	$V_{DS}=15V, V_{GS}=0V$ $f = 1.0MHz$		450		pF
Output Capacitance	$C_{OSS}$			55		pF
Reverse Transfer Capacitance	$C_{RSS}$			16		pF
<b>SWITCHING CHARACTERISTICS</b>						
Turn-On Delay Time	$t_{d(ON)}$	$V_{DD}=50V, V_{GS}=10V, R_G=3\Omega, I_D=5A$		3.8		ns
Rise Time	$t_r$			25.8		ns
Turn-Off Delay Time	$t_{d(OFF)}$			16		ns
Fall Time	$t_f$			8.8		ns
Total Gate Charge	$Q_g(V_{GS}=10V)$	$V_{DS}=50V, V_{GS}=10V, I_D=5A$		11.9		nC
Gate-Source Charge	$Q_{gs}$			2.8		nC
Gate-Drain Charge	$Q_{gd}$			1.7		nC

Note:

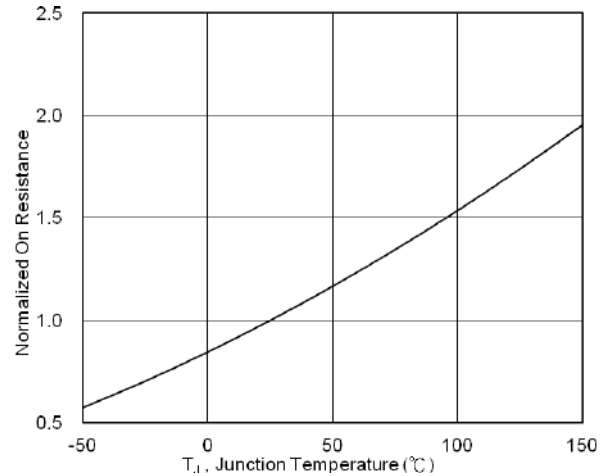
- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.
- The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- The EAS data shows Max. rating . The test condition is  $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=4A$
- The power dissipation is limited by 150°C junction temperature
- The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation



**Fig.3 Forward Characteristics Of Reverse**

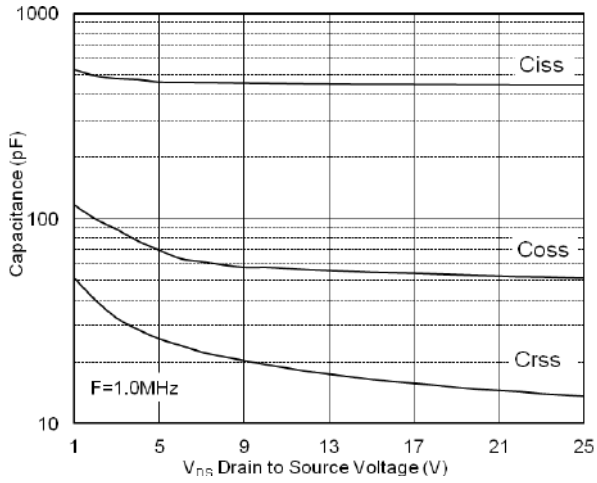


**Fig.4 Gate-Charge Characteristics**

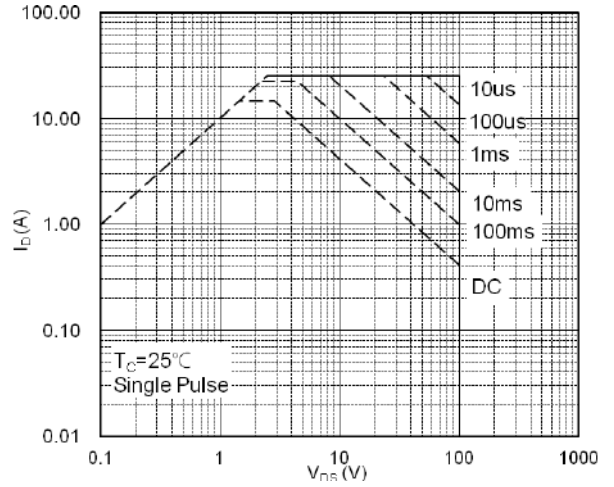


**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**

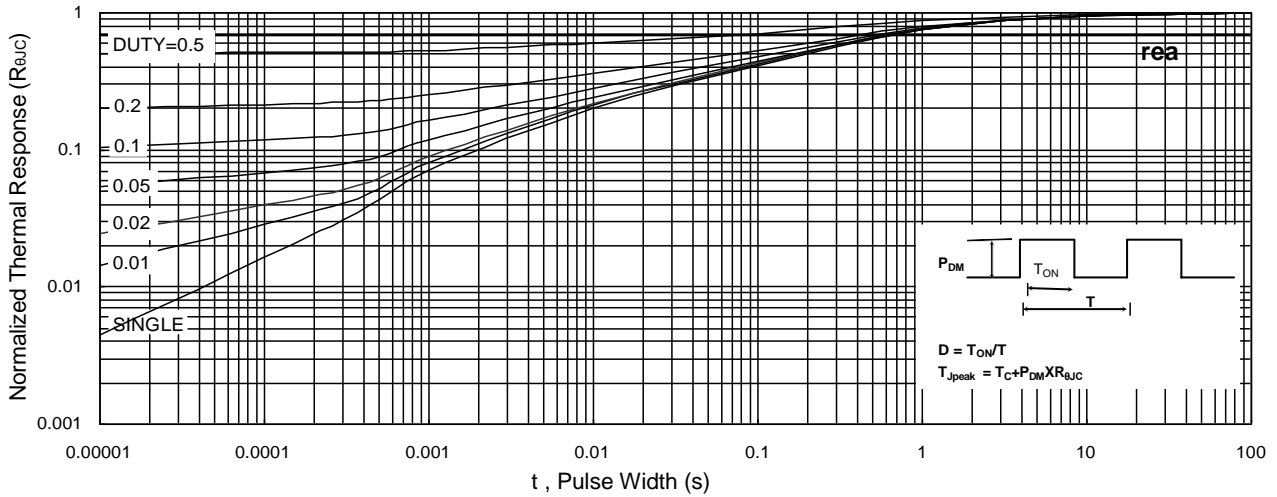
**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**



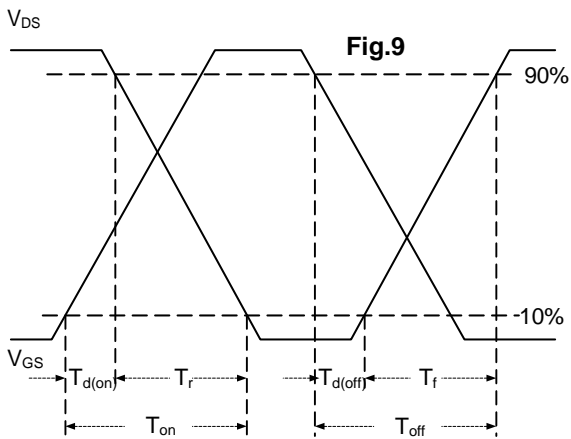
**Fig.7 Capacitance**



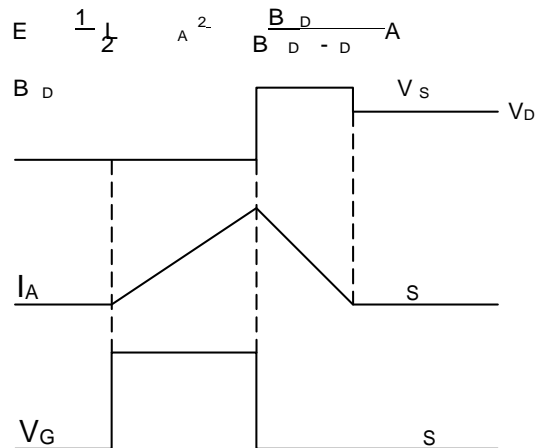
**Fig.8 Safe Operating A**



**Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**